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## State transformation in event driven explicit simulation

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### Abstract:

This paper presents a general method for incorporating **state transformation driven explicit simulation**. One inherent assumption in this type of **simulation** algorithm is the state independence, which allows the algorithm to process the state independently in an **event driven** manner at the transistor level. Numerical problems arise when an inappropriate state representation of the **circuit**, in which the state is not truly independent, is chosen. In principle, any similarity transformation of the state equation can be employed to transform the **circuit** into a more convenient state representation for numerical solution. This paper develops a systematic scheme to derive an appropriate state transformation, and to incorporate the state transformation in such a way as to maintain the efficiency of **event driven explicit simulation** algorithms.

### Index Terms:

[circuit analysis](#) [computing](#) [discrete event simulation](#) [event driven explicit simulation](#) [transformation](#) [simulation algorithm](#) [state equation](#) [state representation](#) [state transformation](#)

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# State Transformation in Event Driven Explicit Simulation

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## Abstract

*This paper presents a general method for incorporating state transformation in event driven explicit simulation. One inherent assumption in this type of simulation algorithm is the state independence which allows the algorithm to process the states independently in an event driven manner at the transistor level. Numerical problems arise when an inappropriate state representation of the circuit, in which the states are not truly independent, is chosen. In principle, any similarity transformation of the state equation can be employed to transform the circuit into a more convenient state space for numerical solution. This paper develops a systematic scheme to derive an appropriate state transformation, and to incorporate the state transformation in such a way to maintain the efficiency of event driven explicit simulation algorithms.*

## 1. Introduction

With design trends continuously moving towards higher clock speed, higher density, and higher levels of integration on chip, the need for fast circuit simulation of large and complex integrated circuits is well known. There have been two major approaches in improving the efficiency of (circuit) transient simulation. Common to all approaches is the use of circuit partitioning and event driven simulation to exploit the spatial sparsity and the temporal latency of large circuits. One approach is to simplify circuit topology to a set of primitives, especially for MOS circuits, in addition to employing simplified device models, such as piecewise quadratic models, to derive the analytical solutions of the node voltages. This approach is embodied in the simulator ILLIADS [3]. The other major approach employs simplified device models to speed up the computation of the numerical solutions during a transient analysis. Piecewise constant (PWC) device models are employed in SPECS [4] and ADAPTS [5]. More general PWL models have been used in various timing analyzers and simulators [1][6]. The Adaptively Controlled Explicit Simulation (ACES) algorithm [2], has been developed to exploit the efficiency of explicit integration algorithm while ensuring the numerical stability of the integration at an incremental cost instead of the full cost of an implicit algorithm. The basic idea is to incrementally approach the steady state while ensuring the stability and efficiency of the integration algorithm.

In event driven simulation, an implicit assumption is that the states are independent so that they can be processed separately. If some of the states are strongly coupled or dependent, these states have to be processed as a group. In other words, the choice of the state variables for a state representation of a given circuit is not appropriate in the sense that the chosen states are not truly independent. This situation arises quite often in extracted circuits, which contain numerous parasitic resistors of small values. For example,

given a resistor as shown in Fig. 1, the two capacitors at the two

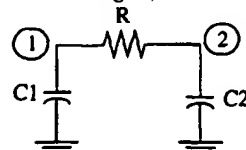


Fig. 1: A simple illustration of the state dependency problem associated with a small value resistor

nodes of the resistor are usually chosen to be the state variables in a typical circuit formulation such as Modified Nodal Analysis (MNA). In the degenerate case of a zero valued resistor or voltage source, the two states are actually the same. Even if the value of the resistance is very small, i.e. the two nodes close to being shorted, then the two chosen state variables are not truly independent. In the following, a number of numerical problems associated with the case of small resistors mentioned above are discussed.

## Matrix ill-conditioning

The first one is the numerical ill conditioning problem due to the resistor being stamped into the MNA circuit matrix equation as a conductance term with  $G = 1/R$  in the admittance form

$$i_R = Gv_R = G(v_1 - v_2).$$

The reason that resistors are stamped as conductors is to avoid introducing extra unknowns into the MNA matrix equation, in which the capacitor voltages and inductor currents are chosen as state variables. However, if  $R$  is small, then  $G$  is large and it may degrade the numerical conditioning of the matrix equation. One way to avoid this problem is to stamp the resistor in its impedance form as

$$v_R - Ri_R = v_1 - v_2 - Ri_R = 0$$

Note that this impedance form introduces the extra unknown current variable  $i_R$  into the matrix equation. Note further that this stamping does not address the state dependency problem though it may alleviate the numerical conditioning problem.

## State Dependency in Explicit Simulation

The state dependency problem is evident in explicit integration algorithm such as Forward Euler (FE). Given the Branch Constitutive Relation (BCR) of a capacitor as  $i_C = C\dot{v}_C$ , the FE stamp of the capacitor at each time  $t$  is given by

$$v_C(t) = v_C(t - \Delta t) + \frac{\Delta t}{C} i_C(t - \Delta t)$$

where  $t - \Delta t$  is the previous time point and  $\Delta t$  is the time step. The above equation represents the BCR of a voltage source, and the

equivalent circuit of the simple structure shown in Fig. 1 using FE integration is shown in Fig. 2 below. As illustrated by Fig. 2, if  $R$  is

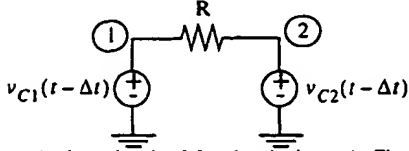


Fig. 2: The equivalent circuit of the circuit shown in Fig. 1 at time  $t$  using an explicit (Forward Euler) integration for the capacitors.

small or zero in the degenerate case, the equivalent circuit includes an illegal loop of voltage sources. This state dependency problem will affect any explicit integration algorithm that simply update the capacitor voltages at a given time using only values at previous time points.

#### State Dependency in Implicit Simulation

The problem of state dependency is handled automatically in an implicit integration scheme because all the states are "implicitly" processed together at the same time. For example, using Backward Euler (BE) as the implicit integration scheme, the stencil of a capacitor in the MNA matrix equation at each time  $t$  can be written as

$$v_C(t) = \frac{\Delta t}{C} i_C(t) + v_C(t - \Delta t) = G_{eq} i_C(t) + V_{eq}$$

In circuit theoretic terms, this equation represents an equivalent circuit consisting of a resistor with conductance  $G_{eq} = (\Delta t)/C$  in series with a voltage source  $V_{eq} = v_C(t - \Delta t)$ . Using these equivalent circuits for the two capacitors, the circuit shown in Fig. 1 can be redrawn as shown in Fig. 3 below. In this case, even if  $R = 0$ , the

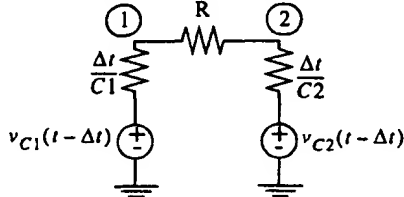


Fig. 3: The equivalent circuit of the circuit shown in Fig. 1 at time  $t$  using an implicit (Backward Euler) integration for the capacitors

two equivalent voltage sources are still decoupled by the two equivalent conductors, and these voltage sources do not form an illegal loop.

The fundamental problem is then how to handle this state dependency problem without resorting to implicit integration algorithms for efficiency reasons. One simple solution is to preprocess a given circuit and delete from the circuit description all the resistors with small values below a specified tolerance. However, this approach may require setting different tolerances for different circuit configurations. Moreover, in some cases, it may be necessary to retain these small resistors in the circuit description. For example, given a long RC interconnect with many taps along the interconnect, it is necessary to retain the small resistors in each RC section of the interconnect to get the total resistance loading of the line. This problem obviates the need to develop an algorithmic approach, other than circuit pruning, to handle this problem. It is the goal of this paper to present such an approach using the event driven Adaptively Controlled Explicit Sim-

ulation (ACES) algorithm as an implementation vehicle. This paper is organized as follows. In section 2 of the paper, a simple example is presented to review the basic ACES algorithm as an implementation vehicle and illustrate the numerical problems due to state dependency. The main results of the paper are presented in section 3. This section discusses a general and systematic method to incorporate state transformation into event driven explicit simulation, especially its implementation in ACES. Section 4 presents some additional examples and simulation results on real circuits using state transformation. Section 5 summarizes the paper.

## 2. State Dependency in Event Driven Explicit Simulation

Consider a simple 2RC circuit as shown in Fig. 4. This simple exam-

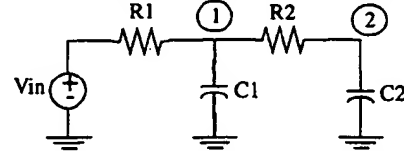


Fig. 4: A simple 2RC example to illustrate the state dependency problem

ple is used to review the basic ACES algorithm and to illustrate the problem of state dependence. The state equation of the circuit can be written as

$$\begin{bmatrix} C_1 & 0 \\ 0 & C_2 \end{bmatrix} \begin{bmatrix} \dot{v}_1 \\ \dot{v}_2 \end{bmatrix} = \begin{bmatrix} -(\frac{1}{R_1} + \frac{1}{R_2}) & \frac{1}{R_2} \\ \frac{1}{R_2} & -\frac{1}{R_2} \end{bmatrix} \begin{bmatrix} v_1 \\ v_2 \end{bmatrix} + \begin{bmatrix} 1 \\ 0 \end{bmatrix} V_{in} \quad (1)$$

where the capacitor voltages have been chosen to be the state variables. Let  $V_{in}$  be a unit step function,  $C_1 = C_2 = 1F$ ,  $R_1 = 1\Omega$ , and  $R_2 = 10^{-6}\Omega$ . Then the state equation can be written as

$$\begin{bmatrix} \dot{v}_1 \\ \dot{v}_2 \end{bmatrix} = \begin{bmatrix} -(1 + 10^6) & 10^6 \\ 10^6 & -10^6 \end{bmatrix} \begin{bmatrix} v_1 \\ v_2 \end{bmatrix} + \begin{bmatrix} 1 \\ 0 \end{bmatrix} V_{in} \quad (2)$$

Assume that the circuit is initially at rest, i.e.  $v_1 = v_2 = 0$  at  $t = 0$ . Also assume a unit step input, i.e.  $V_{in} = 1$  and  $\dot{V}_{in} = 0$  at  $t = 0^+$ . Then, applying the ACES algorithm to compute the time to quiescence [2] for the two states yields  $\Delta t_1 = -(\dot{v}_1(0))/(\ddot{v}_1(0)) \approx 10^{-6}$  and  $\Delta t_2 = 0$ , which implies that the input excitation has not reached the second node at this time point. In other words, one is interested only in non-zero time step at each time point. Hence,  $\Delta t = \Delta t_1 = 10^{-6}$ .

Continue the ACES algorithm to the next time point,  $t_1 = t_0 + \Delta t = 10^{-6}$ . Note that  $v_1$  is now in quiescence and it should not dictate the computation of the next time step. Hence the time to quiescence for  $v_2$  is given by

$$\hat{\Delta t} = -(\dot{v}_2(t_1))/(\ddot{v}_2(t_1)) = 1 + 10^{-6}.$$

Then, at the next time point,  $t_2 = t_1 + \hat{\Delta t}$ , both states will be quiescence and the simulation is completed. The result of this simple simulation for  $v_2$  is shown in Fig. 5 together with the result obtained by AS/X, the IBM internal circuit simulator. Fig. 5 shows the result obtained by ACES with a voltage error tolerance  $\epsilon_v = 0.001$ , where

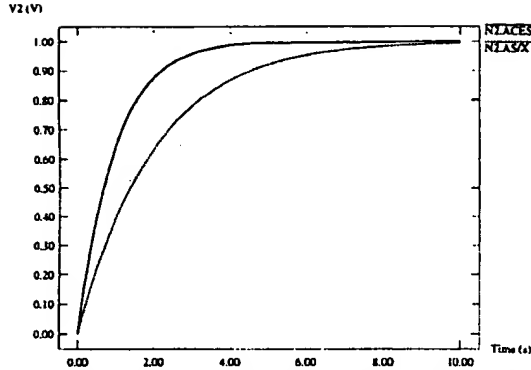


Fig. 5: ACES simulation result (without state transformation) as compared to AS/X for the simple 2RC circuit shown in Fig. 4 with an error tolerance of 0.001.

$\epsilon_v = \frac{1}{2} \ddot{v}(\Delta t)^2$ . Even with this fairly tight tolerance, the ACES result shows significant discrepancy as compared to the AS/X result. This problem is due to the fact that the two states are treated as independent and processed one at a time.

From the circuit point of view, when  $v_1$  enters quiescence, ACES replaces  $C_1$  by a zero valued current source, i. e.  $C_1$  becomes an open circuit and the time constant of this new circuit is given by  $\tau = (R_1 + R_2)C_2 = 1 + 10^{-6}$ . This is exactly the time to quiescence or the time to steady state for this new circuit, assuming a first order approximation for  $v_2$ . However, this is not the correct time constant for the original circuit. Ignoring the effect of the small resistor  $R_2$ , the correct time constant is given by  $\tau = R_1(C_1 + C_2) = 2$ . This discrepancy illustrates the problem in assuming the independence of strongly coupled state variables.

In order to resolve this problem, an appropriate state space representation of the circuit must be chosen in such a way that the states of this space are truly independent. One obvious choice is the eigen-space of the circuit. Compute the eigen-decomposition of the system matrix as

$$A = \begin{bmatrix} -\left(\frac{1}{R_1} + \frac{1}{R_2}\right) & \frac{1}{R_2} \\ \frac{1}{R_2} & -\frac{1}{R_2} \end{bmatrix} = \begin{bmatrix} -(1 + 10^6) & 10^6 \\ 10^6 & -10^6 \end{bmatrix} = T\Lambda T^{-1} \quad (3)$$

where

$$T = \begin{bmatrix} \frac{1}{\sqrt{2}} & \frac{1}{\sqrt{2}} \\ \frac{1}{\sqrt{2}} & -\frac{1}{\sqrt{2}} \end{bmatrix}, T^{-1} = \begin{bmatrix} \frac{1}{\sqrt{2}} & \frac{1}{\sqrt{2}} \\ \frac{1}{\sqrt{2}} & -\frac{1}{\sqrt{2}} \end{bmatrix}, \text{ and } \Lambda = \begin{bmatrix} -2(10^6) & 0 \\ 0 & -0.5 \end{bmatrix} \quad (4)$$

Define the transformed state variables as  $[y_1 \ y_2]^T = T^{-1}[v_1 \ v_2]^T$ . The transformed state equation can then be written as

$$\begin{bmatrix} \dot{y}_1 \\ \dot{y}_2 \end{bmatrix} = \Lambda \begin{bmatrix} y_1 \\ y_2 \end{bmatrix} + T \begin{bmatrix} 1 \\ 0 \end{bmatrix} V_{in} = \Lambda \begin{bmatrix} y_1 \\ y_2 \end{bmatrix} + \begin{bmatrix} 1/\sqrt{2} \\ 1/\sqrt{2} \end{bmatrix} V_{in} \quad (5)$$

Now apply the ACES algorithm to this system. At  $t = 0$ ,  $y_1 = y_2 = 0$ . From the state equations, it can be seen that  $\dot{y}_1 \neq 0$ ,  $\dot{y}_2 \neq 0$ ,  $\ddot{y}_1 \neq 0$ , and  $\ddot{y}_2 \neq 0$ . Hence the time step can be computed as

$$\Delta t = \min(\Delta t_1, \Delta t_2) = \min\left(-\frac{\dot{y}_1}{\ddot{y}_1}, -\frac{\dot{y}_2}{\ddot{y}_2}\right) = \frac{1}{2}(10^{-6})$$

At the next time point  $t_1 = \Delta t = 0.5(10^{-6})$ ,  $\dot{y}_1 = \dot{y}_2 = 0$ . Hence  $y_1$  will stay in quiescence and the time to quiescence for  $y_2$  can be computed as

$$\hat{\Delta t} = -\frac{\dot{y}_2}{\ddot{y}_2} = 0.5$$

In this case, the ACES algorithm captures the correct time constant of the original circuit. This simple example has clearly illustrated the need to select an appropriate state space in which the state variables are truly independent so that an event driven explicit algorithm such as ACES can be applied to provide accurate simulation results.

### 3. State Transformation for Event Driven Explicit Simulation

The eigen-space representation is an ideal space for event driven explicit simulation because the modes of the circuit are decoupled and can be processed sequentially. However, this approach is clearly impractical due to a number of reasons. First the computation of the eigen-decomposition is expensive. Moreover, once the eigen-decomposition is known, the solution can be computed directly without resorting to numerical integration. Avoiding the eigen-decomposition is exactly the goal of numerical integration algorithm. So the question is how to determine an appropriate state transformation. One possible approach is to perform an approximate or inexact eigen-computation. This alleviates the cost of a full eigen-computation. However, for non-linear circuits, an eigen-computation needs to be performed for every new linearization of the nonlinear equations. Another approach is to perform a partial eigen-computation. This is a basically a model reduction problem, especially for large linear circuits. This approach is a standard technique for reduced order modeling of large linear circuits in general nonlinear simulation of circuits with large linear subcircuits. The advantage of this approach is that it can prune out the non dominant eigen-states, such as the state due to the large eigenvalue ( $2(10^6)$ ) in the 2RC example above. However, this approach is not practical for nonlinear circuits.

In general, there is a need to have a simple transformation matrix in order not to degrade the efficiency of event driven explicit simulation technique such as ACES. Note again that one key assumption of circuit level (not logic level or macromodel or block level) event driven simulation is that the states are independent or DC decoupled so that the excitation can be propagated from the input source to the various nodes in the circuit in an event driven manner. For example, the unit step excitation from the input source of the above 2RC circuit will propagate first to node 1, and then to node 2. However, when the two nodes are strongly DC coupled, the algorithm will yield erroneous results as discussed in the previous section. The key idea is to process the two states simultaneously. Note that the eigen-transformation described in the previous section transforms the input matrix

$[1 \ 0]^T$  to  $[1/\sqrt{2} \ 1/\sqrt{2}]^T$ . In the original state space, the input directly affects only  $v_1$ . In the transformed state space, the input directly affects both  $y_1$  and  $y_2$  simultaneously. Hence the key idea in constructing a simple transformation matrix is to make sure that all the transformed states will be dependent on all the original states. In this way, any input that affects at least one state in the original space will affect all the states in the transformed space. In this way, the set of coupled transformed states can be processed simultaneously during the "electrical" event propagation. For the 2RC circuit example, one such simple transformation matrix is given as

$$T = \begin{bmatrix} 1 & -1 \\ 1 & 1 \end{bmatrix} \quad (6)$$

This matrix looks like a simple scaling of the transformation matrix  $T^{-1}$  (the inverse eigenvector matrix) discussed in the previous section. In general, this is not the case. The transformation matrix in Eq. (6) is simply to make every transformed states dependent upon all the original state variables. In order to bring out the effect of the capacitor values, let's choose  $C_1 = 0.5$  and  $C_2 = 2$ . Also select the capacitor charges, denoted by  $q_1$  and  $q_2$  as the state variables in the original space, i. e.  $[q_1 \ q_2]^T = [C_1 v_1 \ C_2 v_2]^T$ . And the transformed state variables are defined as

$$\begin{bmatrix} y_1 \\ y_2 \end{bmatrix} = T \begin{bmatrix} q_1 \\ q_2 \end{bmatrix} = \begin{bmatrix} 1 & -1 \\ 1 & 1 \end{bmatrix} \begin{bmatrix} q_1 \\ q_2 \end{bmatrix}$$

An ACES simulation is then performed for this circuit. Note that the times to quiescence (an "electrical" event in ACES) are computed for the transformed state variables. The local truncation error control is performed for the original state variables (the node voltages) in this case. The waveform at node 2 as obtained by the ACES simulation with state transformation is shown in Fig. 6 together with the AS/X

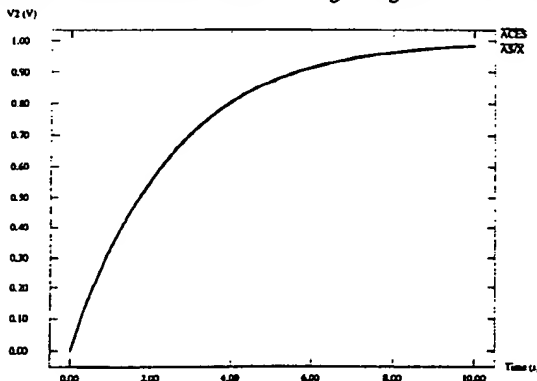


Fig. 6: ACES simulation result (with state transformation) as compared to AS/X for the simple 2RC circuit shown in Fig. 4

simulation result. Note that the state transformation helps ensure the accuracy of ACES simulation.

In general, if there are no coupling among the states, then the transformation matrix is simply an identity matrix. Suppose there are  $n$  coupled states, then the submatrix corresponding to these  $n$  states will be of the form

$$T_{n \times n} = \begin{bmatrix} +1 & -1 & -1 & \dots & -1 \\ +1 & +1 & -1 & \dots & -1 \\ +1 & +1 & +1 & \dots & -1 \\ & & & \dots & \\ +1 & +1 & +1 & \dots & +1 \end{bmatrix}$$

For example, given a circuit with 7 states among which there are two sets of coupled states: {2,3,4} and {6,7}, then the transformation matrix for this circuit can be written as

$$T = \begin{bmatrix} 1 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 1 & -1 & -1 & 0 & 0 & 0 \\ 0 & 1 & 1 & -1 & 0 & 0 & 0 \\ 0 & 1 & 1 & 1 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 1 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 1 & -1 \\ 0 & 0 & 0 & 0 & 0 & 1 & 1 \end{bmatrix}$$

This simple structure allows the transformation matrix to be constructed in a systematic manner during the processing of the circuit. For example, a simple two phase procedure to construct this type of transformation matrix can be described as follows. First initialize the transformation matrix  $T$  to be an identity matrix. Then in the first phase of processing the circuit, check if the terminals (which are assumed to be states for simplicity) or nodes of a given resistive element (or device) are coupled. If the nodes are coupled, then enter the appropriate nonzero entries, which corresponds to the indices of the nodes in the state vector, in the transformation matrix. The purpose of this phase is to record the coupling information in the matrix. In the second phase, the transformation matrix will be processed row by row to determine different groups of coupled states. Then the submatrices of the type described above for these groups of coupled states will be recorded in the transformation matrix.

The next question is how to incorporate state transformation into ACES. A straightforward approach is simply transform the original state equation into a new state equation and perform the analysis in the transformed space. However, it should be noted that the transformed space is used to compute the time to quiescence for the transformed states while the local truncation error is still performed in the original space. Therefore, it is simpler to impose the constitution relation or the quiescence condition for the transformed states in terms of the original states to solve for the necessary variables in the original space. Then the variables in the transformed space can be computed by applying the transformation matrix to the original states. These ideas will be illustrated below using a simple Modified Nodal Analysis (MNA) circuit formulation in the derivative space [2].

In order to simplify the presentation and to bring out the difference between the basic ACES algorithm and the modified algorithm to handle state transformation, assume that there are no inductors,

current sources, floating capacitors, and floating voltage sources. These circuit elements can be incorporated into the formulation in a straightforward manner once the basic algorithm has been established. Under these assumptions, during a quiescence period [2], the MNA formulation of the circuit in the derivative space can be written as

$$\begin{bmatrix} G_{cc} & G_{cv} & E_{cc} & 0 \\ G_{vc} & G_{vv} & 0 & E_v \\ K_c & 0 & E_{qc} & 0 \\ 0 & U_v & 0 & 0 \end{bmatrix} \begin{bmatrix} \dot{v}_c \\ \dot{v}_v \\ \ddot{q}_c \\ \ddot{q}_v \end{bmatrix} = \begin{bmatrix} 0 \\ 0 \\ h_c \\ \dot{v}_v \end{bmatrix} \quad (7)$$

where  $G_{cc}$ ,  $G_{cv}$ ,  $G_{vc}$ , and  $G_{vv}$  are submatrices of the conductance matrix formed by resistive elements;  $E_{cc}$ ,  $E_{qc}$ ,  $E_v$ , and  $U_v$  are submatrices of 1's and 0's to pick out the appropriate capacitor/source voltages or currents;  $K_c$  and  $h_c$  represent the changeable portion of the MNA equation during the simulation depending upon whether the states are in quiescence or not. In general, the first two rows of Eq. (7) represents Kirchoff Current Law (KCL) equations at all voltage and capacitance nodes. The third row represents the Branch Constitutive Relations (BCR) and/or the quiescence conditions for the capacitors. The fourth row represents the BCRs for the voltage sources.

Now define the state transformation  $y_c = Tq_c$ . Initially when all the states are non-quiescent, the BCRs for the transformed states can be written as  $\dot{y}_c = TC\dot{q}_c$ . In circuit theoretic terms, the transformed states can be considered as voltage controlled current sources. In this case, the stamps in the MNA matrix of Eq.(7) can be set as follows:  $K_c = TC$ ,  $E_{qc} = 0$ , and  $h_c = y_c$ . Suppose at time  $t$ , the  $j$ th (transformed) state enters quiescence. Then  $\dot{y}_{cj}(t) = t_j^T \ddot{q}_c(t) = 0$  and the stamps in the MNA matrix can be modified as  $k_{cj}^T = 0$ ,  $e_{qc,j}^T = t_j^T$ , and  $h_{cj} = 0$ , where  $t_j^T$  is the  $j$ th row of  $T$ ,  $k_{cj}^T$  is the  $j$ th row of  $K_c$ , and  $e_{qc,j}^T$  is the  $j$ th row of  $E_{qc}$ . In this case, the transformed state in quiescence can be treated as a zero valued current controlled current source. In this case, partition the vector of transformed states as

$$y_c = \begin{bmatrix} y_{cn} \\ y_{cs} \end{bmatrix} = \begin{bmatrix} T_n \\ T_s \end{bmatrix} q_c \quad (8)$$

where  $y_{cn}$  denotes the subvector of transformed states that are not in quiescence, and  $y_{cs}$  denotes the subvector of transformed states that are in quiescence;  $T_n$  and  $T_s$  are appropriate partitions of the transformation matrix  $T$ . Then the MNA equation as shown in Eq.(7) can be rewritten as

$$\begin{bmatrix} G_{cc} & G_{cv} & E_{cc} & 0 \\ G_{vc} & G_{vv} & 0 & E_v \\ T_n C & 0 & 0 & 0 \\ 0 & 0 & T_s & 0 \\ 0 & U_v & 0 & 0 \end{bmatrix} \begin{bmatrix} \dot{v}_c \\ \dot{v}_v \\ \ddot{q}_c \\ \ddot{q}_v \end{bmatrix} = \begin{bmatrix} 0 \\ 0 \\ y_{cn} \\ 0 \\ \dot{v}_v \end{bmatrix} \quad (9)$$

where the third row of Eq.(9) describes the non-quiescent transformed states, and the fourth row describes the quiescent transformed states. The modified ACES algorithm with state transformation is summarized in the pseudocode below.

#### Algorithm with state transformation:

##### 1. Update sources

##### 2. Update original state variables (for all states):

$$\begin{aligned} \dot{q}_c(t-) &= \dot{q}_c(t-\Delta t) + \ddot{q}_c(t-\Delta t)\Delta t \text{ and} \\ v_c(t-) &= v_c(t-\Delta t) + v_c(t-\Delta t)\Delta t \end{aligned}$$

##### 2b. Update the transformed states:

$$y_c(t-) = T\dot{q}_c(t-) \text{ for quiescent states, and } \dot{y}_c(t-) = 0 \text{ for quiescent states}$$

##### 3. Check quiescence conditions for $y_c$

##### 4. Setup the MNA matrix and solve for $\dot{y}_c(t+)$ , $\ddot{q}_c(t)$ , and $\ddot{q}_v(t)$ .

##### 5. Compute $\dot{q}_c(t+) = C\dot{y}_c(t+)$ and $v_c(t) = C^{-1}\ddot{q}_c(t)$ for all states

##### 5b. Compute $\dot{y}_c(t+) = T\dot{q}_c(t+)$ and $\ddot{y}_c(t) = T\ddot{q}_c(t)$ for non-quiescent states

##### 6. Compute time to quiescence for non-quiescent states, $t_{qs} = -[\dot{y}_c(t)/(\ddot{y}_c(t))]$

##### 7. Set $\Delta t = \min(t_{qs})$

In the above algorithm, the quiescence conditions are checked for the transformed states, not the original states. The advantage of this algorithm is that there is no need to explicitly construct the transformed space. The solution procedure is still performed in the original space with minimal modification of the matrix equation to impose the BCRs and/or the quiescence conditions for the transformed states. In the next section, some examples will be presented to assess the overhead of the modified ACES algorithm and its accuracy as compared with the basic ACES algorithm.

#### 4. Examples

The first example is a simple nonlinear circuit consisting of a driver driving four buffers. Each connection between the driver and a given buffer is an 8 RC interconnect model. The schematic of the circuit is shown in Fig. 7. This example is to illustrate the complica-

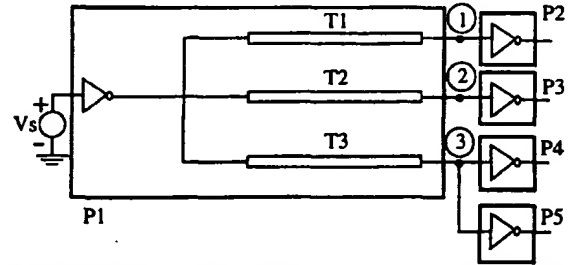


Fig. 7: A simple 5 inverter circuit to illustrate the complication due to circuit partitioning when using state transformation

tion due to circuit partitioning which may couple a port to an internal state of a given partition. This situation arises when parasitic resistances are added to the terminals of a MOSFET model. For example, there are five partitions P1 to P5 in the circuit shown in Fig. 7. Ports numbered 1 to 3 will be coupled to the internal states of partition P1 if the resistor at the end of the lines T1 to T3 are shorted. In a standard ACES algorithm, a partition is processed only if a port attached to the partition has an event. A port event is initiated when the volt-



age slope at the port has an appreciable change. Otherwise, the partition is not processed even if the port information is updated when another partition connected to the same port has an event. For example, assume partition P2 has an event at a given time point. In processing partition P2, the voltage and the slope at port 1 will be updated. If the slope has a significant change (above a given tolerance), then partition P1 will be processed at the same event time. Otherwise, P1 will not be processed. However, in the case port 1 is coupled to an internal state of P1, P1 will have to be processed regardless of whether P1 has a significant change in voltage slope or not. This processing is necessary to take the coupling into account when computing all the necessary information for the next event. A sample run is performed for this circuit with the first, last, and two middle resistors of the lines are shorted to produce different modes of coupling among the internal states and the ports of P1. In this case, the ACES simulation without state transformation requires 309718 events and 34.36 CPU seconds. The ACES simulation with state transformation requires only 3822 events and 2.77 CPU seconds. The ACES simulation results are compared with AS/X simulations and shown in Fig. 8 at the output of partition P2.

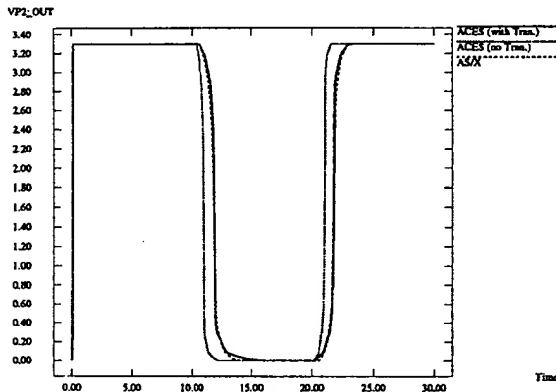


Fig. 8: ACES simulation results (with and without state transformation) as compared to AS/X at the output of partition P2 as shown in Fig. 7.

The last example is an industrial design of a 4 bit ALU. The circuit consists of 282 MOSFETs and 156 nodes. Without parasitic resistances added to the MOSFET models, the ACES simulation requires only 7298 events and 1.17 CPU seconds while the AS/X simulation requires 50 CPU seconds. With a number of parasitic resistances added to the circuit, the AS/X simulation requires about the same 50 CPU seconds. In this case, the ACES simulation with state transformation requires 17640 events and 5.73 CPU seconds. The waveforms at an output node of the circuit as obtained by ACES simulation with and without parasitic resistances and by AS/X are shown in Fig. 9. Note that the difference between the ACES waveforms is due to the state transformation. In the case of no parasitic resistances (and no transformation), the time to quiescence is computed for the original state. In the case of state transformation, the time to quiescence is computed for the transformed states.

## 5. Summary

This paper has identified the dependency of the states in the state space description of a given circuit as the cause for some numerical

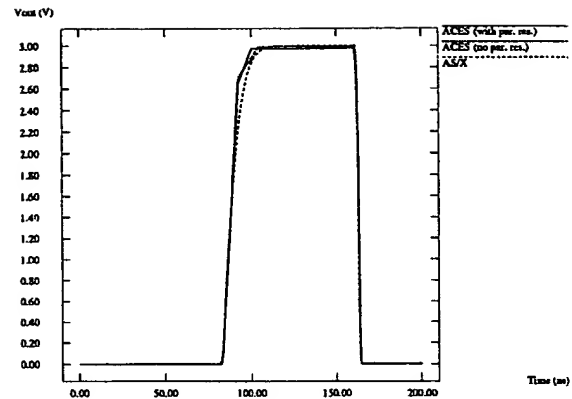


Fig. 9: ACES simulation results (with and without parasitic resistances) as compared to AS/X at the output of an industrial 4 bit ALU circuit.

problems in event driven explicit simulation algorithms such as ACES. State transformation has also been proposed to address this problem. A novel algorithm has been developed to derive systematically a simple state transformation and to include such a transformation in an efficient manner. A number of examples have been included to illustrate the concept and the complication in using state transformation as well as to demonstrate its effectiveness.

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Toshimi Minoura, Shirish S. Pargaonkar, Kurt Reh fuss

 October 1993 **ACM SIGPLAN Notices , Proceedings of the eighth annual conference on Object-oriented programming systems, languages, and applications,**  
Volume 28 Issue 10

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### 2 [Event driven adaptively controlled explicit simulation of integrated circuits](#)

Anirudh Devgan, Ronald A. Rohrer

 November 1993 **Proceedings of the 1993 IEEE/ACM international conference on Computer-aided design**

Full text available: pdf(478.36 KB)

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### 3 [LECSIM: a levelized event driven compiled logic simulation](#)

Zhicheng Wang, Peter M. Maurer

 January 1991 **Conference proceedings on 27th ACM/IEEE design automation conference**

Full text available: pdf(783.84 KB)

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LECSIM is a highly efficient logic simulator which integrates the advantages of event driven interpretive simulation and levelized compiled simulation. Two techniques contribute to the high efficiency. First it employs the zero-delay simulation model with levelized event scheduling to eliminate most unnecessary evaluations. Second, it compiles the central event scheduler into simple local scheduling segments which reduces the overhead of event scheduling. Experimental results show that LECS ...

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Glenn Jennings

 April 1991 **Proceedings of the 24th annual symposium on Simulation**

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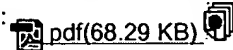
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5 State transformation in event driven explicit simulation

Tuyen V. Nguyen, Anirudh Devgan

November 1997 **Proceedings of the 1997 IEEE/ACM international conference on Computer-aided design**

Full text available:



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This paper presents a general method for incorporating state transformation in event driven explicit simulation. One inherent assumption in this type of simulation algorithm is the state independence, which allows the algorithm to process the states independently in an event driven manner at the transistor level. Numerical problems arise when an inappropriate state representation of the circuit, in which the states are not truly independent, is chosen. In principle, any similarity transformation ...

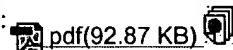
**Keywords:** circuit analysis computing, event driven explicit simulation, similarity transformation, simulation algorithm, state equation, state representation, state transformation

6 A precise event-driven circuit simulator based on predicted fan-in voltages

H. Fujisawa, F. Kawafuji, T. Kitaura, T. Kage

March 1995 **Proceedings of the 1995 European conference on Design and Test**

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We propose a new event-driven circuit simulation method for MOS transistor circuits. This method is based on predicted and revised voltages of nodes, and is highly accurate. Furthermore this method can use an effective block selection function (EBSF) which allows faster simulation with the same accuracy. In industrial circuits, actually our method achieved accuracy equal to or higher than that of a SPICE-like simulator at 3 to 5 times the speed without EBSF, or 11 to 22 times the speed with EBSF ...

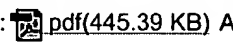
**Keywords:** MOS integrated circuits, MOS transistor circuits, MOSFET circuits, circuit analysis computing, effective block selection function, event-driven circuit simulator, predicted fan-in voltages

7 Incremental event-driven simulation of digital FET circuits

Chandramouli Visweswariah, Jalal A. Wehbeh

July 1993 **Proceedings of the 30th international on Design automation conference**

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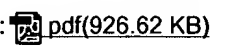
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Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)8 Parallel-and-vector implementation of the event-driven logic simulation algorithm on the Cray Y-MP supercomputer

A. Bataineh, F. Özgüner

December 1992 **Proceedings of the 1992 ACM/IEEE conference on Supercomputing**

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Additional Information: [full citation](#), [references](#), [index terms](#)9 Efficient circuit partitioning algorithms for parallel logic simulation

S. Patil, P. Banerjee, C. Polychronopoulos

August 1989 **Proceedings of the 1989 ACM/IEEE conference on Supercomputing**

Full text available:  pdf(959.59 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

General purpose parallel processing machines are increasingly being used to speed up a variety of VLSI CAD applications. This paper addresses logic simulation on parallel machines by exploiting the concurrency in the circuit being simulated (called data parallelism) as opposed to exploiting parallelism inherent in the simulation algorithm itself (called functional parallelism). The most crucial step in obtaining the maximum parallelism using data parallelis ...

#### 10 Parallel compiled event driven VHDL simulation

V. Krishnaswamy, P. Banerjee

July 1998 **Proceedings of the 12th international conference on Supercomputing**

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#### 11 Power estimation tool for sub-micron CMOS VLSI circuits

F. Rouatbi, B. Haroun, A. J. Al-Khalili

November 1992 **Proceedings of the 1992 IEEE/ACM international conference on Computer-aided design**

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#### 12 A Parallel and Accelerated Circuit Simulator with Precise Accuracy

Peter M. Lee, Shinji Ito, Takeaki Hashimoto, Tomomasa Touma, Hitachi ULSI Systems Co., Junji Sato, Goichi Yokomizo, Semiconductor, Ic, Hitachi, Ltd

January 2002 **Proceedings of the 2002 conference on Asia South Pacific design automation/VLSI Design**

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We have developed a highly parallel and accelerated circuit simulator which produces precise results for large scale simulation. We incorporated multithreading in both the model and matrix calculations to achieve not only a factor of 10 acceleration compared to the defacto standard circuit simulator used worldwide, but also equal or exceed the performance of timing-based event-driven simulators with the accuracy which matches that of SPICE-based circuit simulation. For example, a 89K element D ...

#### 13 Performance evaluation of an event-driven logic simulation machine

F. Hirose

July 1992 **Proceedings of the 29th ACM/IEEE conference on Design automation conference**

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#### 14 A fast signature simulation tool for built-in self-testing circuits

S. B. Tan, K. Totton, K. Baker, P. Varma, R. Porter

October 1987 **24th ACM/IEEE conference proceedings on Design automation conference**

Full text available:  pdf(896.99 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)




This paper describes a Fast Signature Simulator (FSS) tool for Built-In Self-Testing (BIST) circuits. The FSS consists of a simulator generator and a compiled code simulator. The

simulator generator comprises a controlling program called the EXECUTIVE and translation software called SIM-GEN. SIM-GEN accepts a Hardware Description Language (HDL) representation of the circuit-under-test as its input and produces C code simulation modules comprising Boolean relations that represent the structu ...

#### 15 An evaluation of the Chandy-Misra-Bryant algorithm for digital logic simulation

Larry Soulé, Anoop Gupta

October 1991 **ACM Transactions on Modeling and Computer Simulation (TOMACS)**,  
Volume 1 Issue 4

Full text available:  pdf(2.64 MB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

We explore the suitability of the Chandy-Misra-Bryant (CMB) algorithm for the domain of digital logic simulation. Our evaluation is based on results for six realistic benchmark circuits, one of them being the R6000 microprocessor from MIPS. A quantitative evaluation of the concurrency exhibited by the CMB algorithm shows that an average of 42-196 element activations can be evaluated in parallel if arbitrarily many processors are available. One major factor limiting the parallel performance ...



#### 16 A framework for scheduling multi-rate circuit simulation

A. P.-C. Ng, V. Visvanathan

June 1989 **Proceedings of the 1989 26th ACM/IEEE conference on Design automation conference**

Full text available:  pdf(745.68 KB)

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This paper presents a theoretical framework for scheduling of subcircuit simulation in a multirate simulation environment. We show that event-driven simulation, selective-trace, and latency are subsumed by this framework. We assume that the circuit to be simulated is partitioned into subcircuits and that the dependency relations can be expressed as a directed acyclic graph. Each subcircuit predicts its own stepsize, and we assume ...



#### 17 Simulation I: An event-driven transient simulation algorithm for MOS and bipolar circuits

D. Patrick, C. Lyden

March 1990 **Proceedings of the conference on European design automation**

Full text available:  pdf(320.34 KB)

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SUGAR is a program for fast transient simulation of MOS circuits [1]. This paper describes the extension to the algorithm to handle bipolar and BiCMOS circuits. The authors believe that SUGAR is the first event driven circuit simulator which successfully simulates bipolar circuits. The algorithm uses both dynamic and static circuit partitioning to identify closely coupled nodes, and performs simultaneous equation solution on the coupled nodes. A number of other extensions have been made to the a ...



#### 18 Parallel logic simulation of VLSI systems

Mary L. Bailey, Jack V. Briner, Roger D. Chamberlain

September 1994 **ACM Computing Surveys (CSUR)**, Volume 26 Issue 3

Full text available:  pdf(3.74 MB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

Fast, efficient logic simulators are an essential tool in modern VLSI system design. Logic simulation is used extensively for design verification prior to fabrication, and as VLSI systems grow in size, the execution time required by simulation is becoming more and more significant. Faster logic simulators will have an appreciable economic impact, speeding time to market while ensuring more thorough system design testing. One approach to this problem is to utilize parallel processing, taking ...





**Keywords:** circuit structure, parallel architecture, parallelism, partitioning, synchronization algorithm, timing granularity

**19** A predictive system shutdown method for energy saving of event-driven computation

Chi-Hong Hwang, Allen C.-H. Wu

April 2000 **ACM Transactions on Design Automation of Electronic Systems (TODAES)**,  
Volume 5 Issue 2

Full text available:  pdf(121.23 KB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

This paper presents a system-level power management technique for energy savings of event-driven application. We present a new predictive system-shutdown method to exploit sleep mode operations for energy saving. We use an exponential-average approach to predict the upcoming idle period. We introduce two mechanisms, prediction-miss correction and prewake-up, to improve the hit ratio and to reduce the delay overhead. Experiments on four different event-driven applications show that our propo ...

**Keywords:** event-drive, power management, predictive, sleep mode, system shutdown

**20** Incremental circuit simulation using waveform relaxation

Y.-C. Ju, R. A. Saleh

July 1992 **Proceedings of the 29th ACM/IEEE conference on Design automation conference**

Full text available:  pdf(456.22 KB)

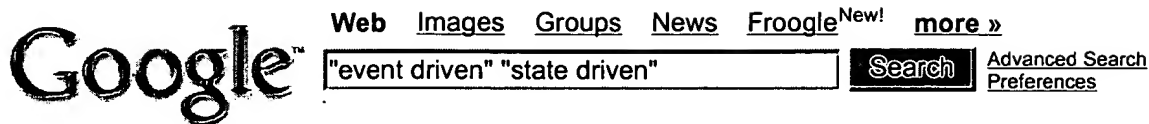
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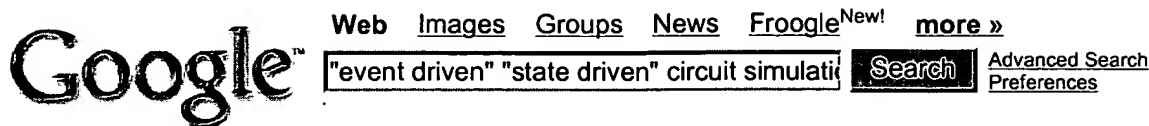
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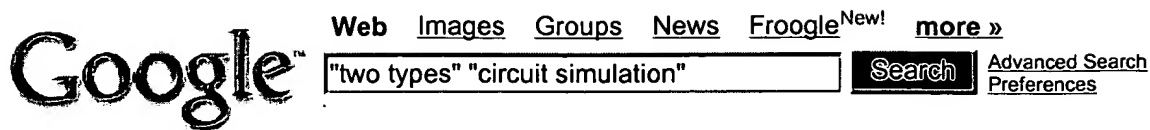
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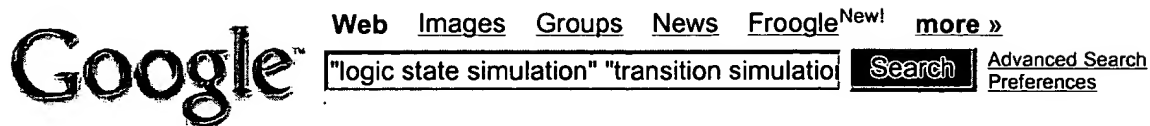
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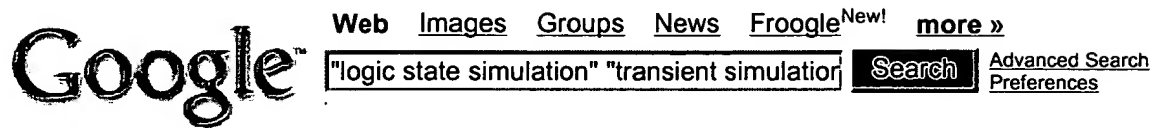
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